Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination
09/544,754	BASANI ET AL.
Examiner	Art Unit
Jungwon Chang	2154

	SEARCHED				
Class	Subclass	Date	Examiner		
709	229	7/18/2005	JWC		
709	244	7/18/2005	JMC		

INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
229	7/18/2005	JMC		
244	7/18/2005	JMC		
	Subclass 229	Subclass Date 229 7/18/2005		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
East text search NPL: Google ACM IEEE search report attached	7/18/2005	JWC	